

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/664,866	TAKAYAMA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Thao P. Le	2818

SEARCHED			
Class	Subclass	Date	Examiner
438	149	8/8/2007	T.LE
257	E51.005	8/8/2007	T.LE
257	E29.151	8/8/2007	T.LE
257	E31.122	8/8/2007	T.LE
257	82	8/9/2007	T.LE
257	83	8/9/2007	T.LE
257	184	8/9/2007	T.LE
257	290	8/9/2007	T.LE
257	436	8/9/2007	T.LE

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
interference (see note)		8/9/2007	T.LE